09 544,675

L Number	Hits	Search Text	DB	Time stamp
1	1032	714/724.ccls.	USPAT	2004/02/24 10:13
2	297	((circuit under test or device under test or unit under test or DUT	USPAT;	2004/02/24 10:15
		or UUT or CUT) and ((((digital signal processor\$1) and (arbitrary	US-PGPUB;	
		waveform generator\$1)) and (clock source)) and (wavform	EPO; JPO;	
		digitizer\$1))) and ((((synchroniz\$3 and single clock source) and	DERWENT;	
		((( signal generator\$1) and (generating and test signal\$1)) and	IBM_TDB	
		((periodic waveform signal digitizer\$1) and (analys\$3 and		
		(response signal\$1 with component\$1 near2 circuit under test)))))		
		and ((analog test near1 measurement) and (on-chip integrated		
		excitation/extracton system\$1))) and (((analog reconstruction		
i		filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit		
		sequence\$1))) and CUT))	l	
3	3637	714/724.ccls. or 714/731.ccls. or 714/726.ccls. or 714/738.ccls. or	USPAT	2004/02/24 10:17
		714/740.ccls. or 714/744.ccls. or 324/76.11.ccls. or		
		324/76.12.ccls. or 324/76.77.ccls. or 324/76.82.ccls. or		
_		324/76.83.ccls.		
5	1639321	analog reconstruction filter\$1	USPAT;	2004/02/24 10:22
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
	40.4000	AAN	IBM_TDB	2004/02/24 40:02
6	404828	extract\$3 and (analog signal\$1 with test signal bit sequence\$1)	USPAT;	2004/02/24 10:23
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
_	211002	(auclas acceptantion filtered) and (automobile) and (auclas	IBM_TDB	2004/02/24 10:24
7	211083	(analog reconstruction filter\$1) and (extract\$3 and (analog	USPAT;	2004/02/24 10:24
		signal\$1 with test signal bit sequence\$1))	US-PGPUB;	
			EPO; JPO; DERWENT;	
			IBM_TDB	
8	1484854	сит	USPAT;	2004/02/24 10:24
•	1404024	COT	US-PGPUB;	2004/02/24 10.24
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
9	50255	((analog reconstruction filter\$1) and (extract\$3 and (analog	USPAT;	2004/02/24 10:24
	30233	signal\$1 with test signal bit sequence\$1))) and CUT	US-PGPUB;	2001,02,2110.21
		Signal Price Signal Die Sequence 1777 und Con	EPO; JPO;	
			DERWENT;	
			IBM_TDB	
10	14991	(((synchroniz\$3 and single clock source) and ((( signal	USPAT;	2004/02/24 10:24
		generator\$1) and (generating and test signal\$1)) and ((periodic	US-PGPUB;	
		waveform signal digitizer\$1) and (analys\$3 and (response signal\$1	EPO; JPO;	
		with component\$1 near2 circuit under test))))) and ((analog test	DERWENT;	
		near1 measurement) and (on-chip integrated excitation/extracton	IBM_TDB	
ļ		system\$1))) and (((analog reconstruction filter\$1) and (extract\$3	_	
		and (analog signal\$1 with test signal bit sequence\$1))) and CUT)		
11	1244861	arbitrary waveform generator\$1	USPAT;	2004/02/24 10:24
			US-PGPUB;	
ļ			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
12	2782117	clock source	USPAT;	2004/02/24 10:25
			US-PGPUB;	
ļ			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
13	14359	wavform digitizer\$1	USPAT;	2004/02/24 10:25
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
	l		IBM_TDB	<u> </u>

14	734308	(digital signal processor\$1) and (arbitrary waveform generator\$1)	USPAT;	2004/02/24 10:25
14	734308	(digital signal processors) and (arbitrary wavelorin generators)	US-PGPUB; EPO; JPO;	2004/02/24 10:23
			DERWENT;	
15	4241389	digital signal processor\$1	IBM_TDB USPAT;	2004/02/24 10:26
15	7271303	digital signal processors:	US-PGPUB;	2004/02/24 10.20
			EPO; JPO;	
			DERWENT; IBM_TDB	
16	399465	((digital signal processor\$1) and (arbitrary waveform	USPAT;	2004/02/24 10:27
		generator\$1)) and (clock source)	US-PGPUB; EPO; JPO;	
			DERWENT;	
1	272040		IBM_TDB	2004/02/24 10:20
17	273842	(digital signal processor\$1) and (((digital signal processor\$1) and (arbitrary waveform generator\$1)) and (clock source))	USPAT	2004/02/24 10:28
18	4024	(wavform digitizer\$1) and ((digital signal processor\$1) and	USPAT	2004/02/24 10:28
		(((digital signal processor\$1) and (arbitrary waveform generator\$1)) and (clock source)))		
19	4024	((wavform digitizer\$1) and ((digital signal processor\$1) and	USPAT	2004/02/24 10:29
		(((digital signal processor\$1) and (arbitrary waveform		·
		generator\$1)) and (clock source)))) and (arbitrary waveform generator\$1)		
20	193	((((synchroniz\$3 and single clock source) and ((( signal	USPAT	2004/02/24 10:29
		generator\$1) and (generating and test signal\$1)) and ((periodic waveform signal digitizer\$1) and (analys\$3 and (response signal\$1)		
		with component\$1 near2 circuit under test))))) and ((analog test		
		near1 measurement) and (on-chip integrated excitation/extracton system\$1))) and (((analog reconstruction filter\$1) and (extract\$3		
		and (analog signal\$1 with test signal bit sequence\$1))) and CUT))		
		and (((wavform digitizer\$1) and ((digital signal processor\$1) and		
		(((digital signal processor\$1) and (arbitrary waveform generator\$1)) and (clock source)))) and (arbitrary waveform		
		generator\$1))		
21	193	((((((synchroniz\$3 and single clock source) and ((( signal generator\$1) and (generating and test signal\$1)) and ((periodic	USPAT	2004/02/24 10:29
		waveform signal digitizer\$1) and (analys\$3 and (response signal\$1		
		with component\$1 near2 circuit under test))))) and ((analog test		
		near1 measurement) and (on-chip integrated excitation/extracton system\$1))) and (((analog reconstruction filter\$1) and (extract\$3		
		and (analog signal\$1 with test signal bit sequence\$1))) and CUT))		
		and (((wavform digitizer\$1) and ((digital signal processor\$1) and (((digital signal processor\$1) and (arbitrary waveform		
		generator\$1)) and (clock source)))) and (arbitrary waveform		
		generator\$1))) and (((analog reconstruction filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1)))		
		and CUT)		
22	193	((((((synchroniz\$3 and single clock source) and ((( signal generator\$1) and (generating and test signal\$1)) and ((periodic	USPAT	2004/02/24 10:29
		waveform signal digitizer\$1) and (analys\$3 and (response signal\$1)		
		with component\$1 near2 circuit under test))))) and ((analog test		
		near1 measurement) and (on-chip integrated excitation/extracton system\$1))) and (((analog reconstruction filter\$1) and (extract\$3		
		and (analog signal\$1 with test signal bit sequence\$1))) and CUT))		
		and (((wavform digitizer\$1) and ((digital signal processor\$1) and (((digital signal processor\$1) and (arbitrary waveform		
		generator\$1)) and (clock source)))) and (arbitrary waveform		
		generator\$1))) and (((analog reconstruction filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1)))		
		and CUT)) and ((analog reconstruction filter\$1) and (extract\$3		
L		and (analog signal\$1 with test signal bit sequence\$1)))		L

23	193	(((((((synchroniz\$3 and single clock source) and ((( signal generator\$1) and (generating and test signal\$1)) and ((periodic waveform signal digitizer\$1) and (analys\$3 and (response signal\$1	USPAT	2004/02/24 10:30
		with component\$1 near2 circuit under test))))) and ((analog test		
		near1 measurement) and (on-chip integrated excitation/extracton system\$1))) and (((analog reconstruction filter\$1) and (extract\$3		
		and (analog signal\$1 with test signal bit sequence\$1))) and CUT)) and (((wavform digitizer\$1) and ((digital signal processor\$1) and		
		(((digital signal processor\$1) and (arbitrary waveform		
		generator\$1)) and (clock source)))) and (arbitrary waveform generator\$1))) and (((analog reconstruction filter\$1) and		
		(extract\$3 and (analog signal\$1 with test signal bit sequence\$1)))		
		and CUT)) and ((analog reconstruction filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1)))) and		
		(extract\$3 and (analog signal\$1 with test signal bit sequence\$1))		
24	193	((((((((signal (() signal generators))))))) and ((periodic generators))) and (generating and test signals)) and ((periodic	USPAT	2004/02/24 10:30
		waveform signal digitizer\$1) and (analys\$3 and (response signal\$1)		
		with component\$1 near2 circuit under test))))) and ((analog test near1 measurement) and (on-chip integrated excitation/extracton		
		system\$1))) and (((analog reconstruction filter\$1) and (extract\$3		
		and (analog signal\$1 with test signal bit sequence\$1))) and CUT)) and (((wavform digitizer\$1) and ((digital signal processor\$1) and		
		(((digital signal processor\$1) and (arbitrary waveform		
		generator\$1)) and (clock source)))) and (arbitrary waveform generator\$1))) and (((analog reconstruction filter\$1) and		
		(extract\$3 and (analog signal\$1 with test signal bit sequence\$1)))		
		and CUT)) and ((analog reconstruction filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1)))) and		
		(extract\$3 and (analog signal\$1 with test signal bit sequence\$1)))		
30	1249	and (analog reconstruction filter\$1) 714/728.ccls. or 714/39.ccls. or 714/30.ccls. or 714/37.ccls. or	USPAT	2004/02/24 10:35
		714/799.ccls.		
32 26	5054 193	327/?.ccls. or 324/?.ccls. or 714/?.ccls. ((((((((((((((((((((((((((((((((((((	USPAT USPAT	2004/02/24 10:36 2004/02/24 10:37
	155	generator\$1) and (generating and test signal\$1)) and ((periodic	00,7	200 1, 02, 2 1 2010
		waveform signal digitizer\$1) and (analys\$3 and (response signal\$1 with component\$1 near2 circuit under test))))) and ((analog test		
		near1 measurement) and (on-chip integrated excitation/extracton		
		system\$1))) and (((analog reconstruction filter\$1) and (extract\$3 and (analog signal\$1 with test signal bit sequence\$1))) and CUT))		
		and (((wavform digitizer\$1) and ((digital signal processor\$1) and		
		(((digital signal processor\$1) and (arbitrary waveform generator\$1)) and (clock source)))) and (arbitrary waveform		
		generator\$1))) and (((analog reconstruction filter\$1) and		
		(extract\$3 and (analog signal\$1 with test signal bit sequence\$1))) and CUT)) and ((analog reconstruction filter\$1) and (extract\$3		
		and (analog signal\$1 with test signal bit sequence\$1)))) and		:
		(extract\$3 and (analog signal\$1 with test signal bit sequence\$1))) and (analog reconstruction filter\$1)) and (((circuit under test or		
		device under test or unit under test or DUT or UUT or CUT) and		:
		((((digital signal processor\$1) and (arbitrary waveform generator\$1)) and (clock source)) and (wavform digitizer\$1))) and		
		((((synchroniz\$3 and single clock source) and ((( signal		
		generator\$1) and (generating and test signal\$1)) and ((periodic waveform signal digitizer\$1) and (analys\$3 and (response signal\$1		
		with component\$1 near2 circuit under test))))) and ((analog test		
		near1 measurement) and (on-chip integrated excitation/extracton system\$1))) and (((analog reconstruction filter\$1) and (extract\$3		
		and (analog signal\$1 with test signal bit sequence\$1))) and CUT)))		